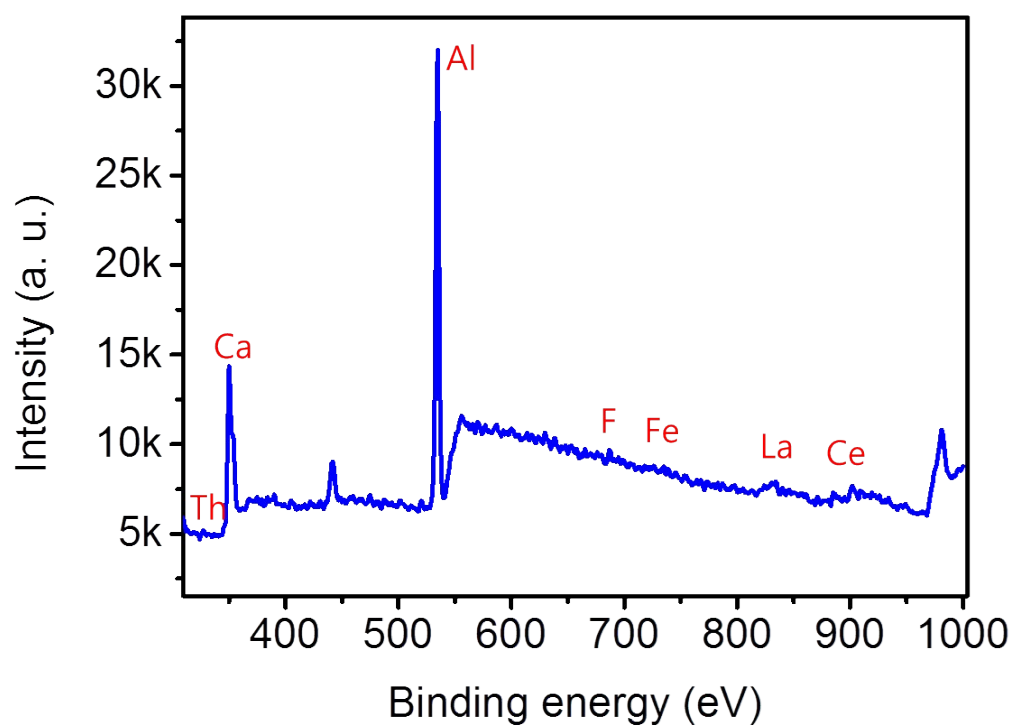


### Electronic supporting information



ESI-1. XPS analysis of the 50 nm thin film.